

# FDP027N08B\_F102 N-Channel PowerTrench® MOSFET 80 V, 223 A, 2.7 mΩ

## Features

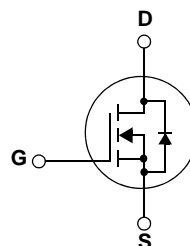
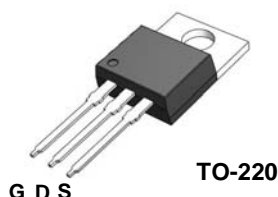
- $R_{DS(on)} = 2.21 \text{ m}\Omega$  (Typ.) @  $V_{GS} = 10 \text{ V}$ ,  $I_D = 100 \text{ A}$
- Low FOM  $R_{DS(on)} \cdot Q_G$
- Low Reverse Recovery Charge,  $Q_{rr} = 112 \text{ nC}$
- Soft Reverse Recovery Body Diode
- Enables Highly Efficiency in Synchronous Rectification
- Fast Switching Speed
- 100% UIL Tested
- RoHS Compliant

## Description

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench® process that has been tailored to minimize the on-state resistance while maintaining superior switching performance.

## Applications

- Synchronous Rectification for ATX / Server / Telecom PSU
- Battery Protection Circuit
- Motor Drives and Uninterruptible Power Supplies



## MOSFET Maximum Ratings $T_C = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	FDP027N08B_F102	Unit
$V_{DSS}$	Drain to Source Voltage	80	V
$V_{GSS}$	Gate to Source Voltage	$\pm 20$	V
$I_D$	Drain Current	-Continuous ( $T_C = 25^\circ\text{C}$ , Silicon Limited)	223*
		-Continuous ( $T_C = 100^\circ\text{C}$ , Silicon Limited)	158*
		-Continuous ( $T_C = 25^\circ\text{C}$ , Package Limited)	120
$I_{DM}$	Drain Current	- Pulsed (Note 1)	892
$E_{AS}$	Single Pulsed Avalanche Energy	(Note 2)	917
$dv/dt$	Peak Diode Recovery $dv/dt$	(Note 3)	6.0
$P_D$	Power Dissipation	( $T_C = 25^\circ\text{C}$ )	246
		- Derate above $25^\circ\text{C}$	1.64
$T_J, T_{STG}$	Operating and Storage Temperature Range	-55 to +175	$^\circ\text{C}$
$T_L$	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds	300	$^\circ\text{C}$

\*Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 120A

## Thermal Characteristics

Symbol	Parameter	FDP027N08B_F102	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max	0.61	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max	62.5	

## Package Marking and Ordering Information

Device Marking	Device	Package	Description	Quantity
FDP027N08B	FDP027N08B_F102	TO-220	F102: Trimmed Leads	50

## Electrical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
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### Off Characteristics

$BV_{DSS}$	Drain to Source Breakdown Voltage	$I_D = 250\mu\text{A}$ , $V_{GS} = 0\text{V}$	80	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = 250\mu\text{A}$ , Referenced to $25^\circ\text{C}$	-	0.05	-	$\text{V}/^\circ\text{C}$
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 64\text{V}$ , $V_{GS} = 0\text{V}$	-	-	1	$\mu\text{A}$
		$V_{DS} = 64\text{V}$ , $T_C = 150^\circ\text{C}$	-	-	500	
$I_{GSS}$	Gate to Body Leakage Current	$V_{GS} = \pm 20\text{V}$ , $V_{DS} = 0\text{V}$	-	-	$\pm 100$	nA

### On Characteristics

$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS} = V_{DS}$ , $I_D = 250\mu\text{A}$	2.5	-	4.5	V
$R_{DS(on)}$	Static Drain to Source On Resistance	$V_{GS} = 10\text{V}$ , $I_D = 100\text{A}$	-	2.21	2.7	$\text{m}\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS} = 10\text{V}$ , $I_D = 100\text{A}$	-	227	-	S

### Dynamic Characteristics

$C_{iss}$	Input Capacitance	$V_{DS} = 40\text{V}$ , $V_{GS} = 0\text{V}$ $f = 1\text{MHz}$	-	10170	13530	pF
$C_{oss}$	Output Capacitance		-	1670	2220	pF
$C_{rss}$	Reverse Transfer Capacitance		-	35	-	pF
$C_{oss(er)}$	Engry Related Output Capacitance	$V_{DS} = 40\text{V}$ , $V_{GS} = 0\text{V}$	-	3025	-	pF
$Q_{g(tot)}$	Total Gate Charge at 10V	$V_{DS} = 40\text{V}$ , $V_{GS} = 10\text{V}$ $I_D = 100\text{A}$	-	137	178	nC
$Q_{gs}$	Gate to Source Gate Charge		-	56	-	nC
$Q_{gs2}$	Gate Charge Threshold to Plateau		-	25	-	nC
$Q_{gd}$	Gate to Drain "Miller" Charge		-	28	-	nC
ESR	Equivalent Series Resistance (G-S)	$f = 1\text{MHz}$	-	2.4	-	$\Omega$

### Switching Characteristics

$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 40\text{V}$ , $I_D = 100\text{A}$ $V_{GS} = 10\text{V}$ , $R_{GEN} = 4.7\Omega$	-	47	104	ns
$t_r$	Turn-On Rise Time		-	66	142	ns
$t_{d(off)}$	Turn-Off Delay Time		-	87	184	ns
$t_f$	Turn-Off Fall Time		-	41	92	ns

### Drain-Source Diode Characteristics

I <sub>S</sub>	Maximum Continuous Drain to Source Diode Forward Current		-	-	223*	A
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current		-	-	892	A
V <sub>SD</sub>	Drain to Source Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>SD</sub> = 100A	-	-	1.3	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0V, V <sub>DD</sub> = 40V, I <sub>SD</sub> = 100A dI <sub>F</sub> /dt = 100A/μs	-	80	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge		-	112	-	nC

#### Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature
2.  $L = 3\text{mH}$ ,  $I_{AS} = 24.72\text{A}$ ,  $R_G = 25\Omega$ , Starting  $T_J = 25^\circ\text{C}$
3.  $I_{SD} \leq 100\text{A}$ ,  $di/dt \leq 200\text{A}/\mu\text{s}$ ,  $V_{DD} \leq BV_{DSS}$ , Starting  $T_J = 25^\circ\text{C}$
4. Essentially Independent of Operating Temperature Typical Characteristics

# Typical Performance Characteristics

Figure 1. On-Region Characteristics

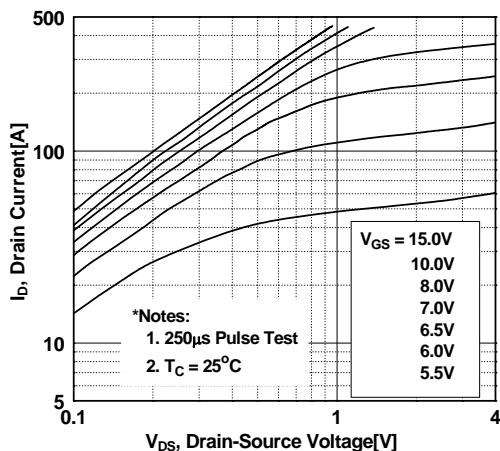


Figure 2. Transfer Characteristics

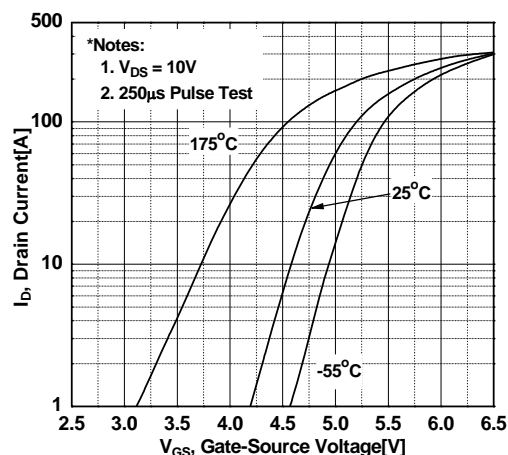


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

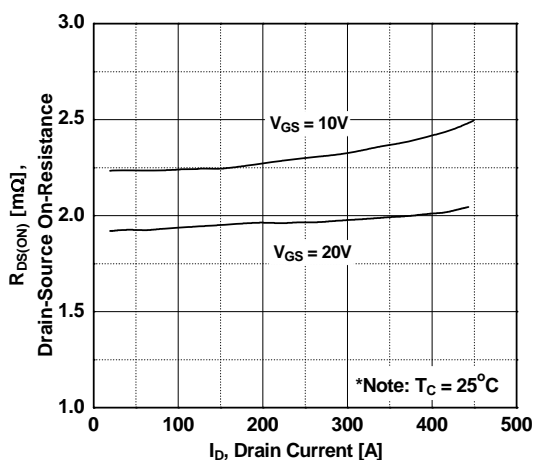


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

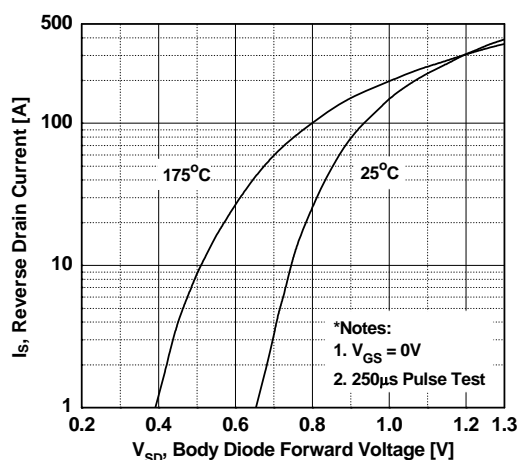


Figure 5. Capacitance Characteristics

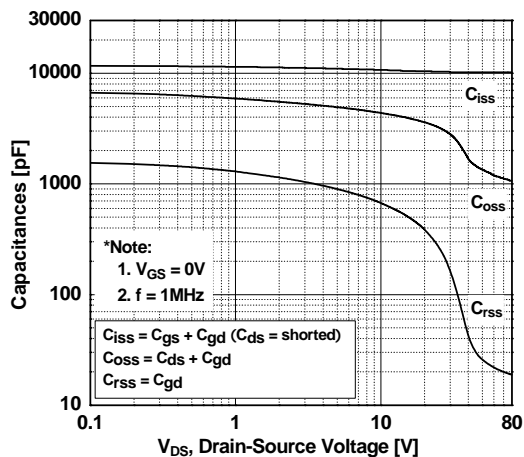
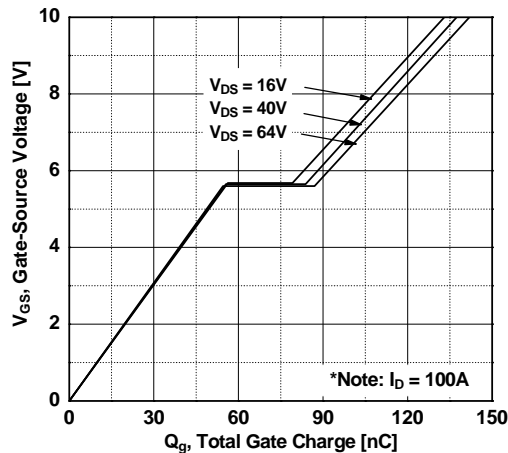


Figure 6. Gate Charge Characteristics



# Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

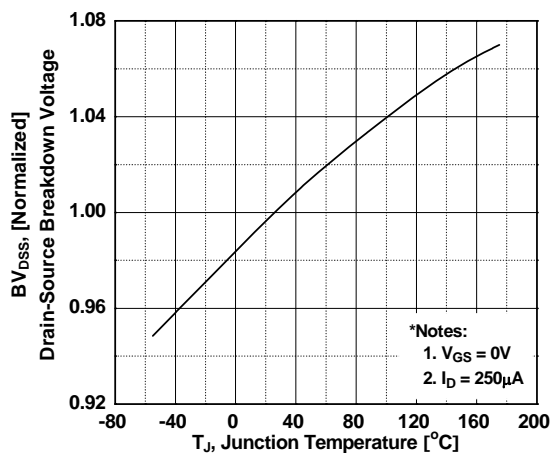


Figure 8. On-Resistance Variation vs. Temperature

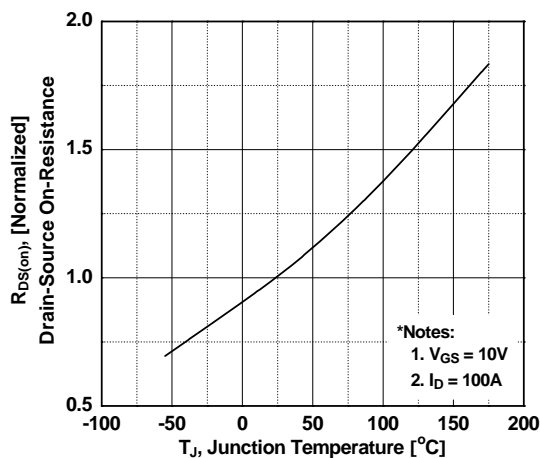


Figure 9. Maximum Safe Operating Area vs. Case Temperature

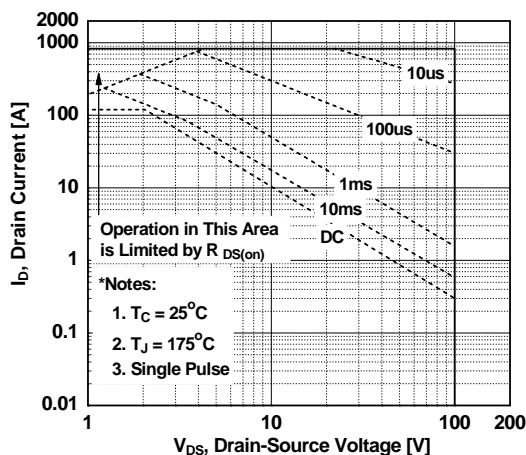


Figure 10. Maximum Drain Current

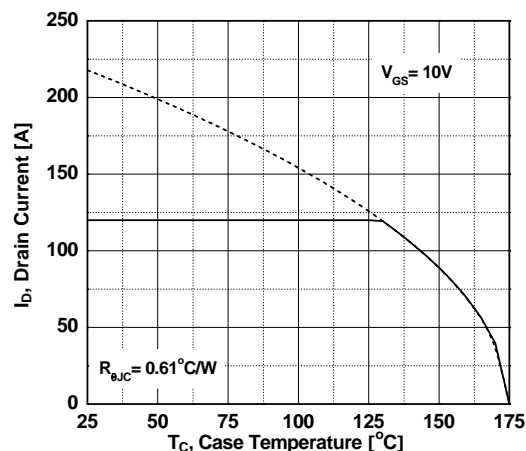


Figure 11. Eoss vs. Drain to Source Voltage Switching Capability

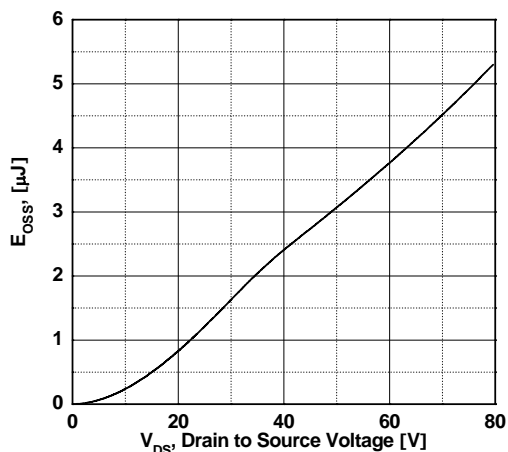
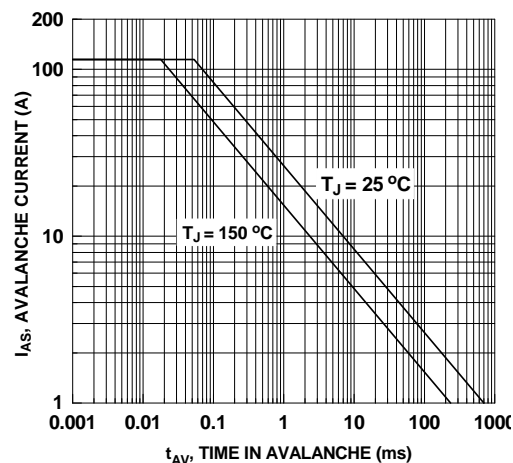
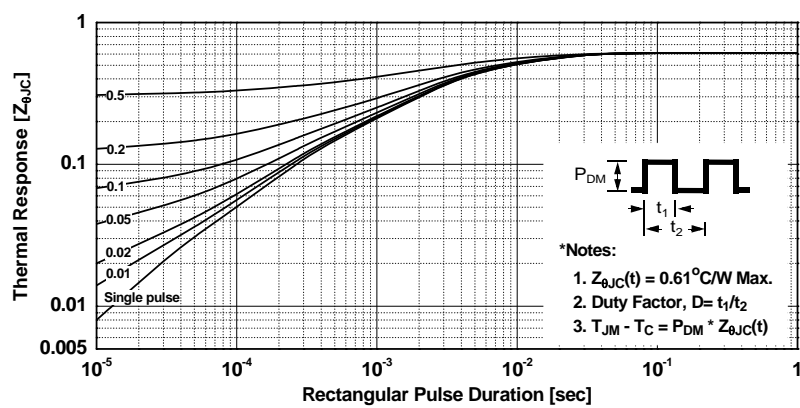


Figure 12. Unclamped Inductive



# Typical Performance Characteristics (Continued)

## Figure 13. Transient Thermal Response Curve



Gate Charge Test Circuit & Waveform



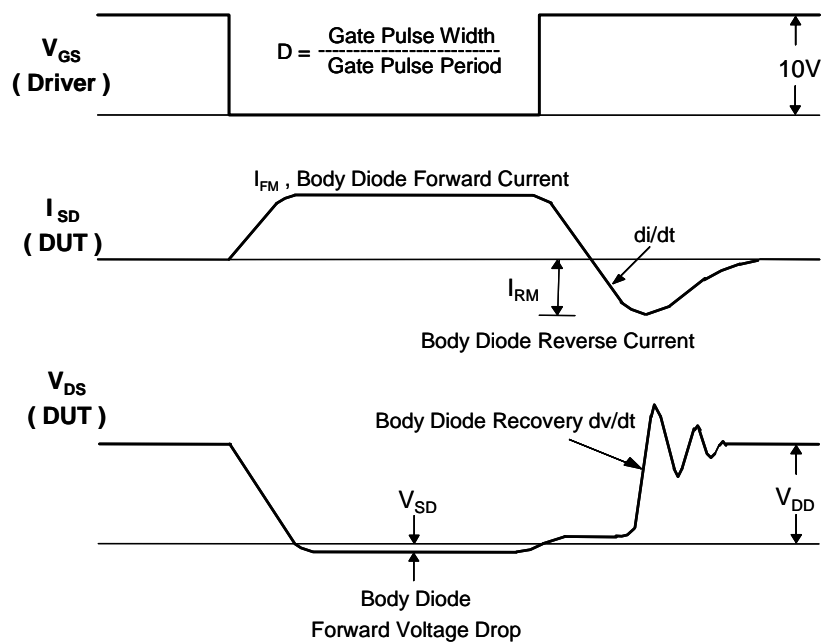
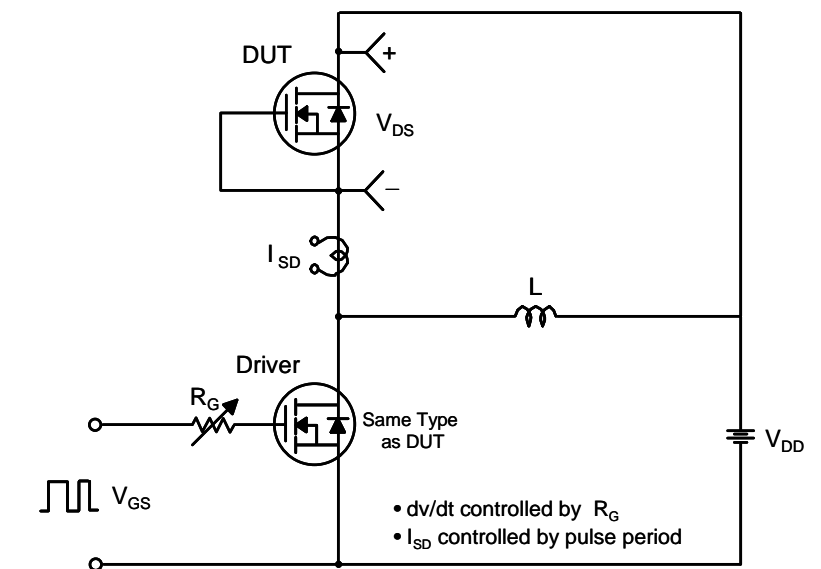
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching Test Circuit & Waveforms

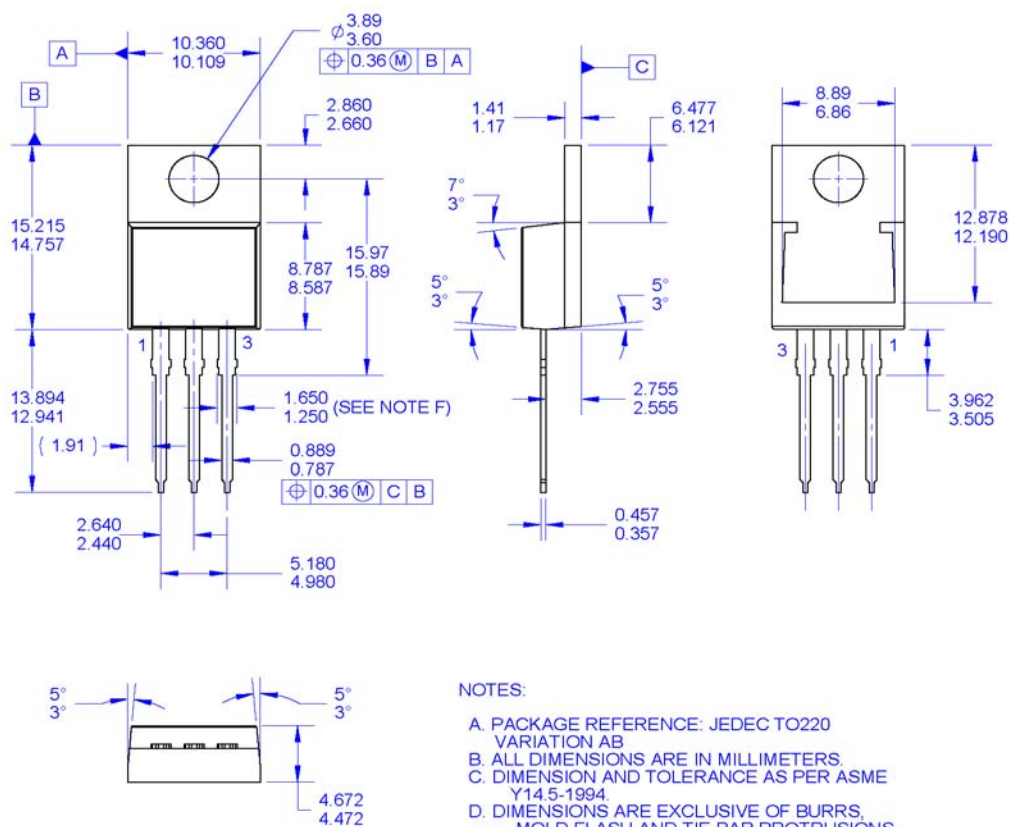


# Peak Diode Recovery dv/dt Test Circuit & Waveforms



# Mechanical Dimensions

## TO-220 (F102: Trimmed Leads)







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